## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination NIIYAMA ET AL. | Examiner | Art Unit | Jean F. Duverne | 2839 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0097974 A1	07-2002	Matsumoto et al.	385/137
	В	US-2002/0009268	01-2002	Matsumoto et al.	385/80
	С	US-2003/0021573 A1	01-2003	Matsumoto et al.	385/137
	D	US-2001/0024560	09-2001	Inoue, Masakatsu	385/137
	E	US-6,553,173 B1	04-2003	Goto, Akio	385/137
	F	US-6,549,713 B1	04-2003	Pi et al.	385/137
	G	US-2003/0012544 A1	01-2003	Matsumoto et al.	385/137
	Н	US-			
	ı	US-			
	7	US-			
	к	US-			,
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	x					

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